
Viri napak pri uporabi elektrokemijske impedančne spektroskopije pri preiskavah premazov in drugih snovi (ISO/TR 5602:2021)

Sources of error in the use of electrochemical impedance spectroscopy for the investigation of coatings and other materials (ISO/TR 5602:2021)

Fehlerquellen bei der Anwendung elektrochemischer Elektroimpdanzspektroskopie bei der Untersuchung von Beschichtungen und anderer Stoffe (ISO/TR 5602:2021)

Sources d'erreur dans l'utilisation de la spectroscopie d'impédance électrochimique pour l'étude des revêtements et autres matériaux (ISO/TR 5602:2021)

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Sources of error in the use of electrochemical impedance spectroscopy for the investigation of coatings and other materials

*Sources d'erreur dans l'utilisation de la spectroscopie d'impédance
électrochimique pour l'étude des revêtements et autres matériaux*

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Contents

Page

Foreword	v
Introduction	vi
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 Error in the make-up of the measuring cell	1
4.1 Roughness of the surface	1
4.2 O-ring — Considerations about the precise determination of the exposed area	3
4.3 Faulty cell make-up	7
4.3.1 Optically detectable leaks	7
4.3.2 Optically non-detectable causes	7
4.4 Reference electrodes	9
4.4.1 General information on the distance between the reference and working electrodes	9
4.4.2 Shielding	11
4.4.3 Air bubble in the reference electrode	11
4.4.4 Poisoning of the reference electrode	11
4.4.5 Bleeding of the reference electrode	11
4.5 Counter electrodes	11
4.5.1 Relative sizes	11
4.5.2 Reactive counter electrodes	11
4.6 Gas inclusions in the measuring cell	11
5 Faults caused by electronics incl. shielding	12
5.1 Faraday cage	12
5.2 Extended cable (without active shielding)	15
5.3 Cable breaks	16
5.4 Contact resistances between metallic contacts and the working electrode/counter electrode	17
5.5 Inductivities	18
5.6 Measurement range switching	19
5.7 Scattering signals in power supply	20
5.8 Insufficient signal-to-noise ratio	22
5.9 Influence of peripheral devices	22
6 Parameter selection, measurement range limits	24
6.1 Open-lead test	24
6.2 Note on dummy cells – ISO 16773-3	24
6.3 Unsuitable amplitude	24
6.4 Insufficient frequency range	26
6.5 Repetition rate for subsequent measurements	27
7 Non-stationary measurement conditions	28
7.1 General	28
7.2 Temperature fluctuations	29
7.3 Electrolytic conductivity	31
7.4 Swelling	31
7.5 Drifting OCP	31
7.6 Corroding working electrode	33
7.7 Reactive counter electrodes	33
7.8 Gas formation at the counter electrode	33
8 Design and selection of equivalent circuit diagrams	34
8.1 Constant phase element	34
8.2 Multiple possibilities for the selection of equivalent circuits	35

ISO/TR 5602:2021(E)

8.3	Warburg impedance	37
9	Significance of measurement values from equivalent circuits	37
9.1	Measurement uncertainty	37
9.2	Plausibility analysis	38
10	Interpretation of the measurement values of various coating systems	39
10.1	Pre-treatment	39
10.2	Film thickness and measurement surface	40
10.3	Number of layers	41
10.4	Conditioning	45
10.5	Generic type of binder	45
11	Presentation of data	45
Annex A (informative)	Calculation of the coating capacitance	48
Annex B (informative)	Further information on the influence of the double-layer capacitance	49
Annex C (informative)	Estimation of the order of magnitude of an apparent capacitance caused by corrosion	50
Bibliography		52

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see www.iso.org/iso/foreword.html.

This document was prepared by Technical Committee ISO/TC 35, *Paints and varnishes*, Subcommittee SC 9, *General test methods for paints and varnishes*.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Introduction

Electrochemical impedance spectroscopy is described in detail in ISO 16773-1 to ISO 16773-4. It became apparent during use of these standards that sources of error and measurement artefacts that lead to incorrect interpretations are not dealt with comprehensively. This document supplements the ISO 16773 series of standards to deal with this issue.

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Sources of error in the use of electrochemical impedance spectroscopy for the investigation of coatings and other materials

1 Scope

This document describes the main sources of error in the use of electrochemical impedance spectroscopy for the investigation of coatings and other materials. The sources of error listed here include all process steps from the set-up of the sample with the measuring cell right through to evaluation.

NOTE The sources of error discussed here do not represent a complete list.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 4618, *Paints and varnishes — Terms and definitions*

ISO 16773-1, *Electrochemical impedance spectroscopy (EIS) on coated and uncoated metallic specimens — Part 1: Terms and definitions*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 4618, ISO 16773-1 and the following apply.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- ISO Online browsing platform: available at <https://www.iso.org/obp>
- IEC Electropedia: available at <https://www.electropedia.org/>

3.1

limit impedance

minimum or maximum impedance that can be measured using the impedance spectrometer

3.2

limit frequency

minimum or maximum frequency that can be set on the impedance spectrometer

4 Error in the make-up of the measuring cell

4.1 Roughness of the surface

A wet and rough surface could conduct stray currents to a scratch or artificial defect, see [Figure 1](#). This could yield in a spectrum showing a much lower resistance than in reality. Examples of spectra are shown in [Figure 2](#).

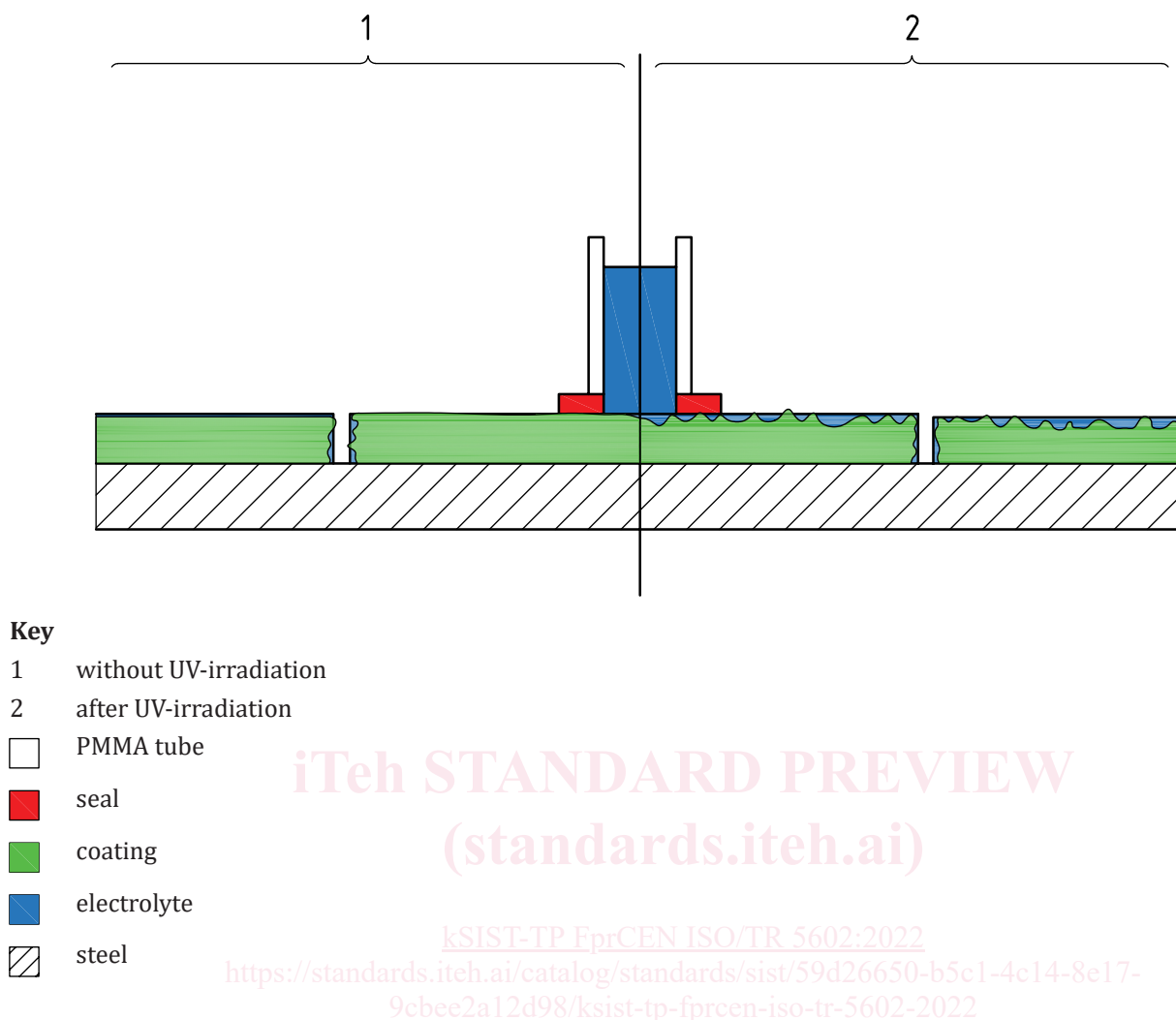


Figure 1 — Conductive path from counter electrode to scratch due to surface roughness

The rough surface was measured on the unscratched area. Although the rough surface was dried with a tissue, the residual amount of water was sufficient to produce a conductive path via the scratch to the substrate. As result, the spectrum of the sample resulted in the incorrect identification of a defective coating. After 2 h of continuous immersion in the cell, the surface outside the cell had dried and the conductive path was interrupted, which resulted in a typical spectrum of an intact coating.

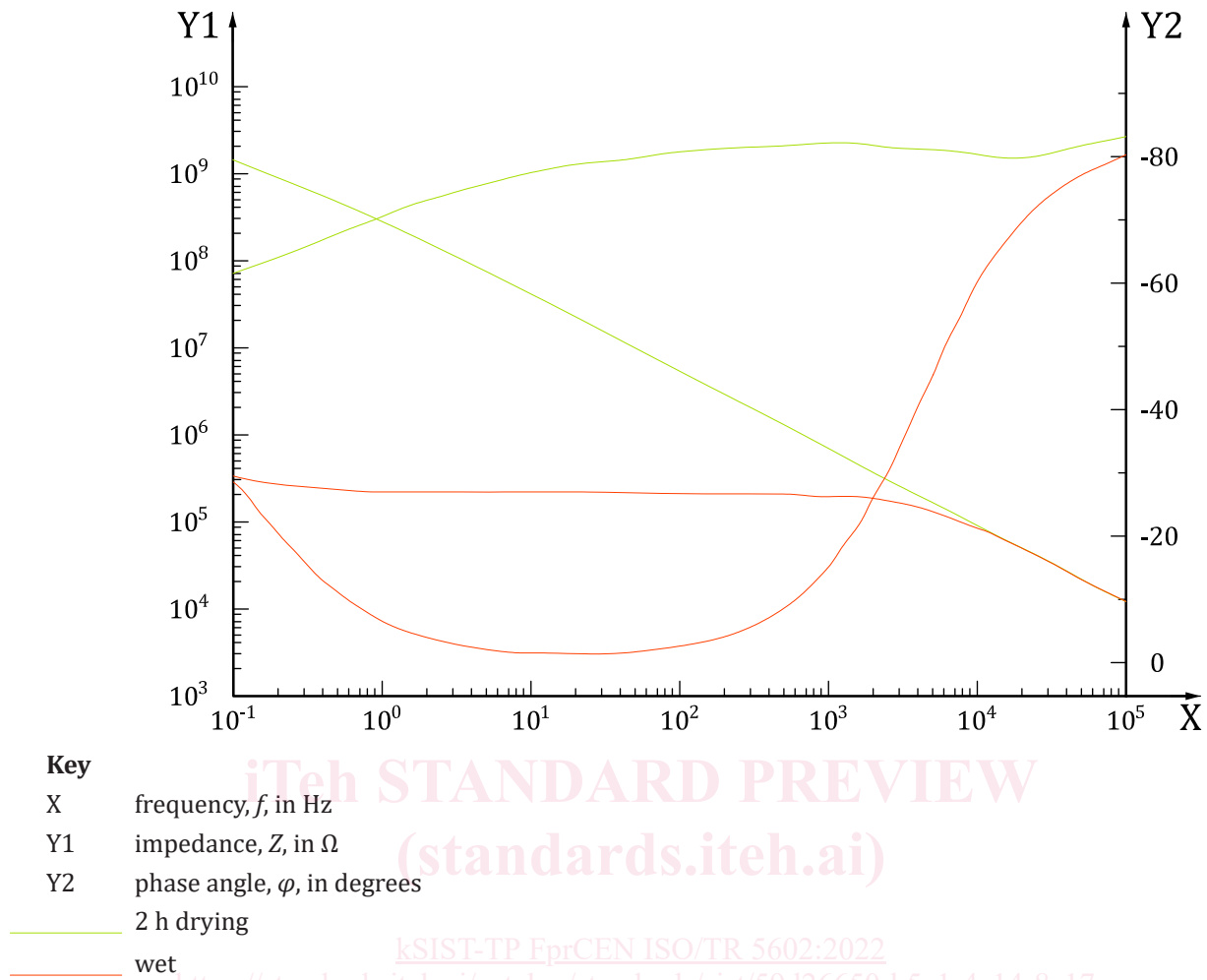
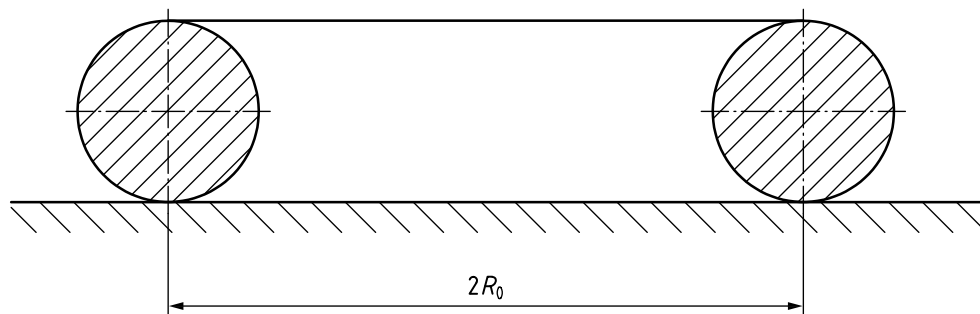


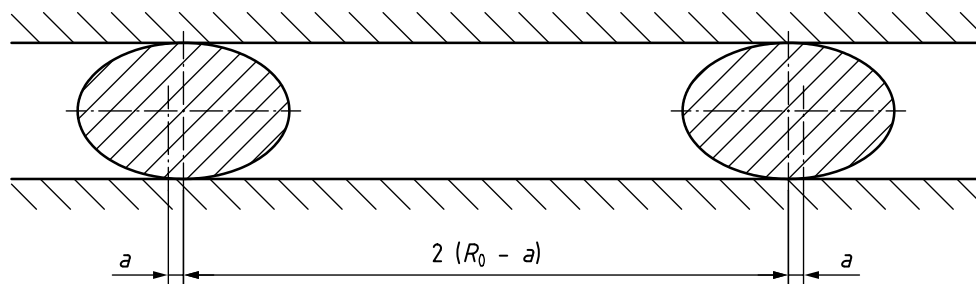
Figure 2 — EIS spectra of the initially wet coating and 2 h after drying

4.2 O-ring — Considerations about the precise determination of the exposed area

If an O-ring is used to seal the cell, the exposed area is smaller than the theoretically assumed area because the O-ring will be compressed, and therefore, the exposed area will be reduced (see [Figure 3](#)).



a) Ideal situation, uncompressed



b) Real situation, compressed

Key R_0 radius of the uncompressed O-ring a difference in the radius of the O-ring due to compression**Figure 3 — Uncompressed and compressed O-ring**

This behaviour can be visualized easily by using two transparent PMMA (poly methylene methacrylate) plates which were compressed with 4 screws. The screws were gently tightened only by hand and without any tools.

[Figure 4](#) shows the set-up and [Figure 5](#) and [Figure 6](#) show the compressed O-rings of 1,2 cm and 5 cm diameter, respectively.

**Figure 4 — Compression of O-ring using 4 screws**

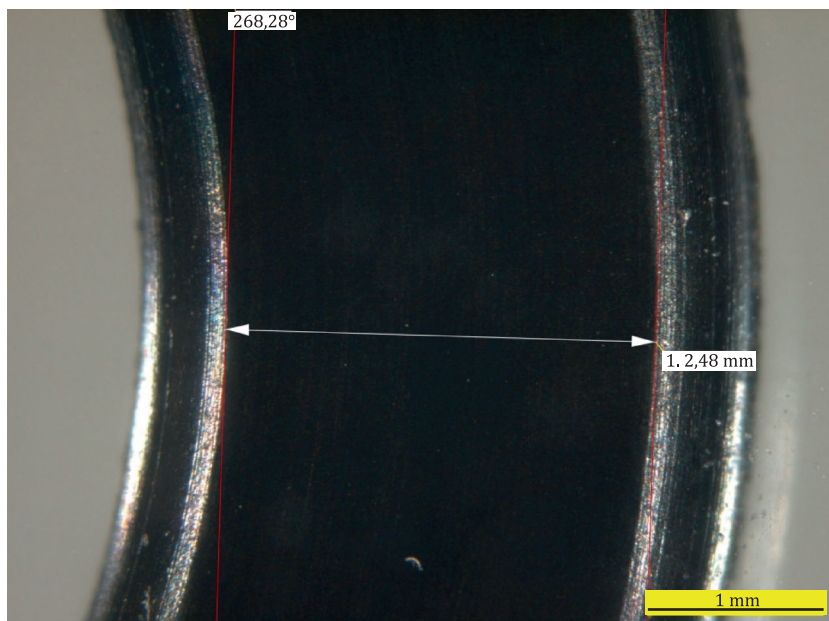


Figure 5 — Compressed O-ring of 1,2 cm diameter

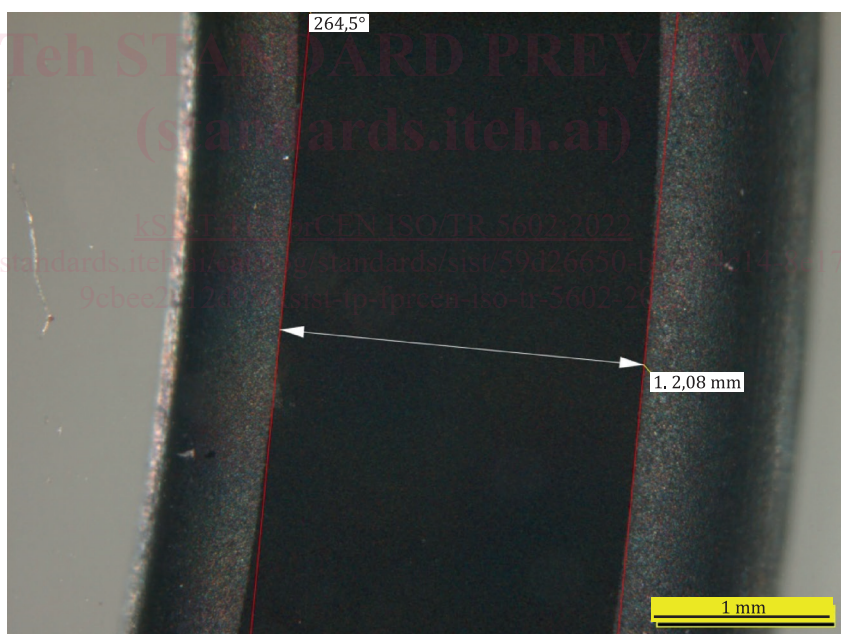
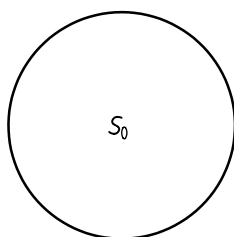


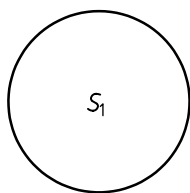
Figure 6 — Compressed O-ring of 5 cm diameter

The exposed area can be calculated as illustrated in [Figure 7](#).



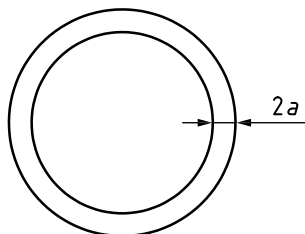
$$S_0 = \pi \cdot R_0^2$$

a) O-ring not compressed — Contact surface of the specimen with testing solution



$$S_1 = \pi \cdot (R_0 - a)^2$$

b) O-ring compressed — Contact surface of the specimen with testing solution



$$\Delta S = S_0 - S_1 = \pi \cdot R_0^2 - \pi \cdot (R_0 - a)^2$$

c) Reduction of contact surface of specimen due to O-ring compression

Key

- S_0 geometric area with the O-ring uncompressed
- S_1 exposed area with the O-ring compressed
- ΔS difference $S_0 - S_1$
- R_0 radius of the uncompressed O-ring
- a difference of the radius of the O-ring due to compression

Figure 7 — Calculation of the exposed area

The error dS between exposed area S_1 and geometric area S_0 can be approximated depending on the O-ring radius, R_0 , and the measured contact, $2a$, using [Formula \(1\)](#):

$$dS = \frac{\Delta S}{S_0} \cdot 100 = \frac{2 \cdot a \cdot R_0 \cdot a^2}{R_0^2} \cdot 100 \quad (1)$$

Some examples for calculation of the error of the exposed area are shown in [Table 1](#).

Table 1 — Approximate error estimation of contact surface of specimens in corrosion cells

Radius of the uncompressed O-ring R_0 mm	Difference in the radius of the O-ring due to compression a mm	$R_0 - a$ mm	Geometric area with the O-ring uncompressed (theoretical surface) S_0 mm ²	Exposed area with the O-ring compressed (real surface) S_1 mm ²	Error of the exposed area dS %
6	0,8	5,2	113	85	25
12	0,8	11,2	452	394	13
24	0,8	23,2	1 809	1 690	7
30	0,8	29,2	2 826	2 677	5
6	1	5	113	79	31
12	1	11	452	380	16
24	1	23	1 809	1 661	8
30	1	29	2 826	2 641	7
6	1,25	4,75	113	71	37
12	1,25	10,75	452	363	20
24	1,25	22,75	1 809	1 625	10
30	1,25	28,75	2 826	2 595	8

4.3 Faulty cell make-up

4.3.1 Optically detectable leaks

Optically detectable leaks in the measuring cell are obvious and are not dealt with here.

4.3.2 Optically non-detectable causes

The behaviour shown in [Figure 8](#) was observed in a non-reproducible manner for a very well-documented coating (cathodic e-coat) that is in familiar use in measurement technology. This behaviour occurred with varying amounts of pressure on the measuring cell at different locations on the same test panels; however, a direct relationship was not detected.

If the behaviour shown in [Figure 8](#) is observed in a measuring cell, the measuring cell is not suitable.

Generally, every measurement set-up is tested for errors with a familiar system before this measuring cell is used on an unfamiliar system.